

Dual N-channel 40 V, 7.2 mΩ logic level MOSFET

5 December 2013

Product data sheet

## 1. General description

Dual logic level N-channel MOSFET in an LFPAK56D (Dual Power-SO8) package using TrenchMOS technology. This product has been designed and qualified to AEC Q101 standard for use in high performance automotive applications.

## 2. Features and benefits

- Dual MOSFET
- Q101 Compliant
- Repetitive avalanche rated
- Suitable for thermally demanding environments due to 175 °C rating
- True logic level gate with  $V_{GS(th)}$  rating of greater than 0.5 V at 175 °C

## 3. Applications

- 12 V Automotive systems
- Motors, lamps and solenoid control
- Transmission control
- Ultra high performance power switching

## 4. Quick reference data

Table 1. Qui	ck reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	-	40	V
I <sub>D</sub>	drain current	V <sub>GS</sub> = 5 V; T <sub>mb</sub> = 25 °C; <u>Fig. 1</u>		-	-	40	А
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>		-	-	64	W
Static character	eristics FET1 and FET2	·					
R <sub>DSon</sub>	drain-source on-state resistance	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>		-	6	7.2	mΩ
Dynamic chara	acteristics FET1 and FE	T2	·	·			
Q <sub>GD</sub>	gate-drain charge	$I_D$ = 10 A; $V_{DS}$ = 32 V; $V_{GS}$ = 5 V; T <sub>j</sub> = 25 °C; Fig. 13; Fig. 14		-	6.8	-	nC





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## 5. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S1	source1	8 7 6 5	D1 D1 D2 D2
2	G1	gate1		
3	S2	source2		
4	G2	gate2		
5	D2	drain2		 S1 G1 S2 G2
6	D2	drain2		mbk725
7	D1	drain1	1 2 3 4 LFPAK56D (SOT1205)	
8	D1	drain1		

# 6. Ordering information

Table 3. Ordering information							
Type number	Package	e					
	Name	Description	Version				
BUK9K6R8-40E	LFPAK56D	Plastic single ended surface mounted package (LFPAK56D); 8 leads	SOT1205				

## 7. Marking

Table 4. Marking codes	
Type number	Marking code
BUK9K6R8-40E	96E840

# 8. Limiting values

#### Table 5.Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V <sub>DS</sub>	drain-source voltage	T <sub>j</sub> ≥ 25 °C; T <sub>j</sub> ≤ 175 °C		-	40	V
V <sub>DGR</sub>	drain-gate voltage	R <sub>GS</sub> = 20 kΩ		-	40	V
V <sub>GS</sub>	gate-source voltage	$T_j \le 175 \ ^{\circ}C; Pulsed$	[1][2]	-15	15	V
		T <sub>j</sub> ≤ 175 °C; DC		-10	10	V
I <sub>D</sub>	drain current	T <sub>mb</sub> = 25 °C; V <sub>GS</sub> = 5 V; <u>Fig. 1</u>		-	40	А
		T <sub>mb</sub> = 100 °C; V <sub>GS</sub> = 5 V; <u>Fig. 1</u>		-	40	А
I <sub>DM</sub>	peak drain current	$T_{mb}$ = 25 °C; pulsed; $t_p \le 10 \ \mu$ s; Fig. 4		-	265	А
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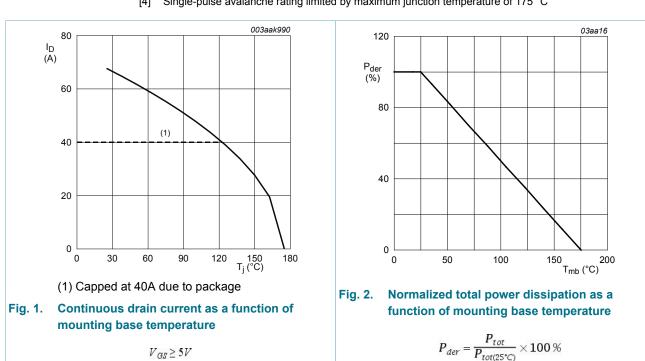
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Symbol	Parameter	Conditions		Min	Мах	Unit
P <sub>tot</sub>	total power dissipation	T <sub>mb</sub> = 25 °C; <u>Fig. 2</u>		-	64	W
T <sub>stg</sub>	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-drain	diode FET1 and FET2					
I <sub>S</sub>	source current	T <sub>mb</sub> = 25 °C		-	40	А
I <sub>SM</sub>	peak source current	pulsed; $t_p \le 10 \ \mu s$ ; $T_{mb} = 25 \ ^\circ C$		-	265	А
Avalanche R	uggedness FET1 and FET2					
E <sub>DS(AL)S</sub>	non-repetitive drain-source avalanche energy	$I_{D} = 40 \text{ A}; V_{sup} \le 40 \text{ V}; V_{GS} = 10 \text{ V};$ $T_{j(init)} = 25 \text{ °C}; \underline{Fig. 3}$	[3][4]	-	125	mJ

[1] Accumulated Pulse duration up to 50 hours delivers zero defect ppm

[2] Significantly longer life times are achieved by lowering T<sub>i</sub> and or V<sub>GS</sub>.

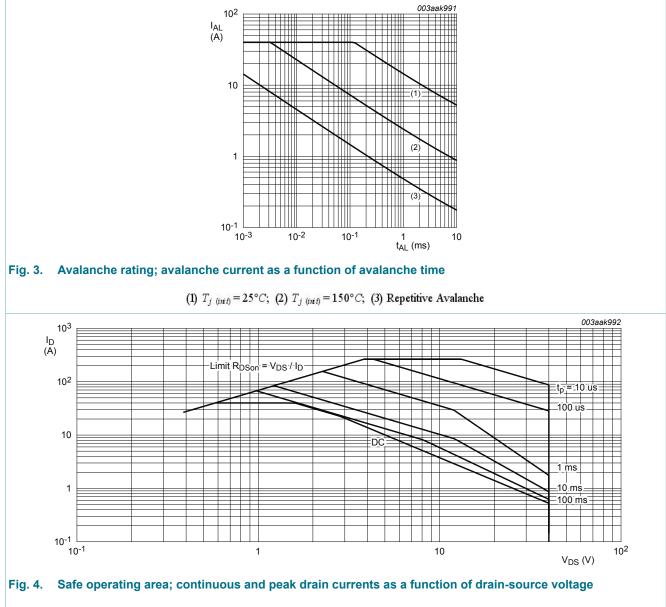
[3] Refer to application note AN10273 for further information



[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C

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 $T_{mb} = 25^{\circ}C; \ I_{DM}$  is a single pulse

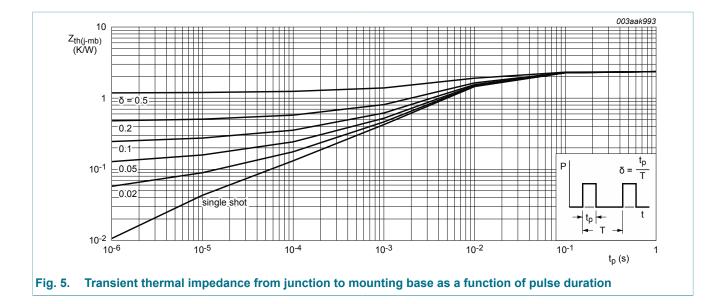
## 9. Thermal characteristics

Table 6. The	able 6. I nermai characteristics						
Symbol	Parameter	Conditions		Min	Тур	Мах	Unit
R <sub>th(j-mb)</sub>	thermal resistance from junction to mounting base	<u>Fig. 5</u>		-	-	2.36	K/W
R <sub>th(j-a)</sub>	thermal resistance from junction to ambient	Minimum footprint; mounted on a printed circuit board		-	95	-	K/W

#### Table 6. Thermal characteristics

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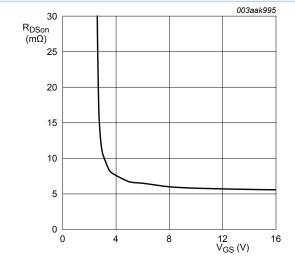
## **10. Characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	acteristics FET1 and FET2	· · · ·	I			
V <sub>(BR)DSS</sub>	drain-source	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = -55 °C	36	-	-	V
	breakdown voltage	$I_D$ = 250 µA; $V_{GS}$ = 0 V; $T_j$ = 25 °C	40	-	-	V
V <sub>GS(th)</sub>	gate-source threshold voltage	$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = 25 °C; Fig. 9; Fig. 10	1.4	1.7	2.1	V
		I <sub>D</sub> = 1 mA; V <sub>DS</sub> = V <sub>GS</sub> ; T <sub>j</sub> = 175 °C; Fig. 9; Fig. 10	0.5	-	-	V
		$I_D$ = 1 mA; $V_{DS}$ = $V_{GS}$ ; $T_j$ = -55 °C; Fig. 9; Fig. 10	-	-	2.45	V
I <sub>DSS</sub>	drain leakage current	$V_{DS}$ = 40 V; $V_{GS}$ = 0 V; $T_j$ = 175 °C	-	-	500	μA
		$V_{DS}$ = 40 V; $V_{GS}$ = 0 V; $T_j$ = 25 °C	-	0.02	1	μA
I <sub>GSS</sub>	gate leakage current	$V_{GS}$ = -10 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	2	100	nA
		$V_{GS}$ = 10 V; $V_{DS}$ = 0 V; $T_j$ = 25 °C	-	2	100	nA
R <sub>DSon</sub>	drain-source on-state	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 25 °C; <u>Fig. 11</u>	-	6	7.2	mΩ
	resistance	V <sub>GS</sub> = 5 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 175 °C; Fig. 11	-	12.1	14.5	mΩ
		V <sub>GS</sub> = 10 V; I <sub>D</sub> = 10 A; T <sub>j</sub> = 25 °C; Fig. 11; Fig. 12	-	5	6.1	mΩ
Dynamic ch	naracteristics FET1 and FE	T2				_
Q <sub>G(tot)</sub>	total gate charge	$I_D$ = 10 A; $V_{DS}$ = 32 V; $V_{GS}$ = 5 V;	-	22.2	-	nC
Q <sub>GS</sub>	gate-source charge	T <sub>j</sub> = 25 °C; <u>Fig. 13</u> ; <u>Fig. 14</u>	-	5.2	-	nC

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Symbol	Parameter	Conditions		Min	Тур	Мах	Unit
$Q_{GD}$	gate-drain charge			-	6.8	-	nC
C <sub>iss</sub>	input capacitance	V <sub>GS</sub> = 0 V; V <sub>DS</sub> = 25 V; f = 1 MHz;		-	2250	3000	pF
C <sub>oss</sub>	output capacitance	T <sub>j</sub> = 25 °C; <u>Fig. 15</u>		-	305	366	pF
C <sub>rss</sub>	reverse transfer capacitance			-	148	202	pF
t <sub>d(on)</sub>	turn-on delay time	$V_{DS}$ = 32 V; R <sub>L</sub> = 3.2 Ω; V <sub>GS</sub> = 5 V; R <sub>G(ext)</sub> = 5 Ω; T <sub>j</sub> = 25 °C; I <sub>D</sub> = 10 A		-	13	-	ns
t <sub>r</sub>	rise time			-	22	-	ns
t <sub>d(off)</sub>	turn-off delay time			-	27	-	ns
t <sub>f</sub>	fall time			-	20	-	ns
Source-dra	ain diode FET1 and FET2						
V <sub>SD</sub>	source-drain voltage	$I_{S}$ = 25 A; $V_{GS}$ = 0 V; $T_{j}$ = 25 °C; <u>Fig. 16</u>		-	0.78	1.2	V
t <sub>rr</sub>	reverse recovery time	$I_{S} = 10 \text{ A; } dI_{S}/dt = -100 \text{ A}/\mu\text{s; } V_{GS} = 0 \text{ V;}$ $V_{DS} = 20 \text{ V; } T_{j} = 25 \text{ °C}$		-	23	-	ns
Qr	recovered charge			-	18	-	nC





 $T_j = 25^{\circ}C; \ I_D = 10A$ 

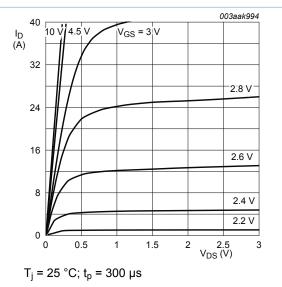
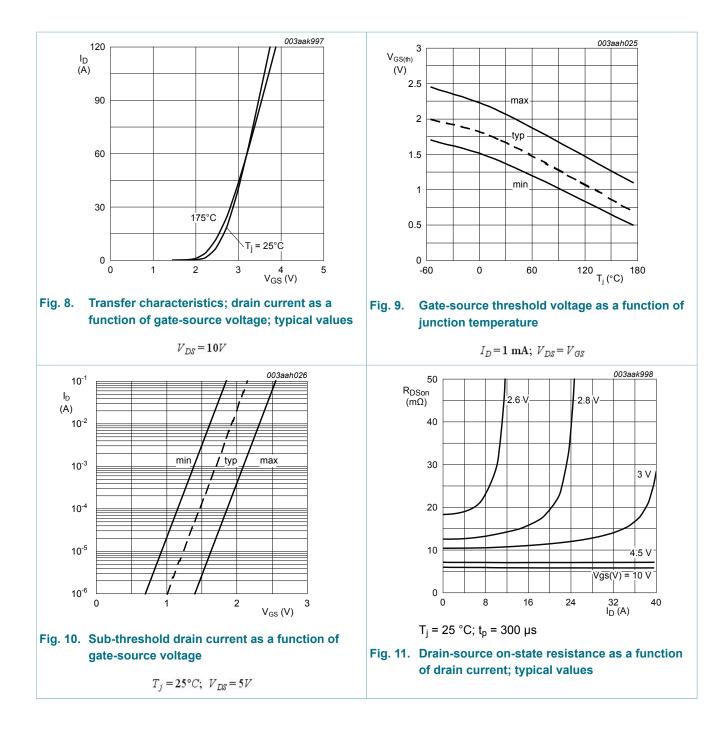


Fig. 7. Output characteristics; drain current as a function of drain-source voltage; typical values

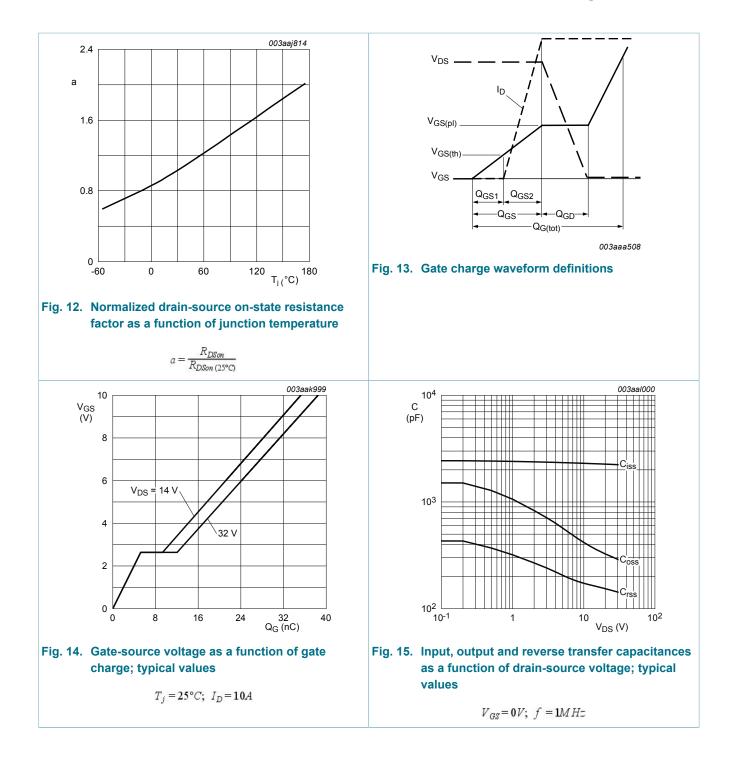
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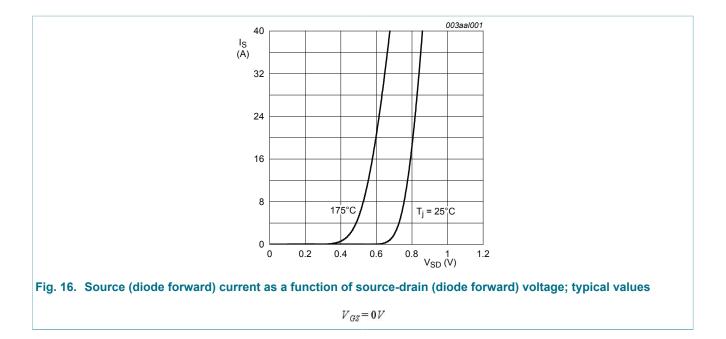
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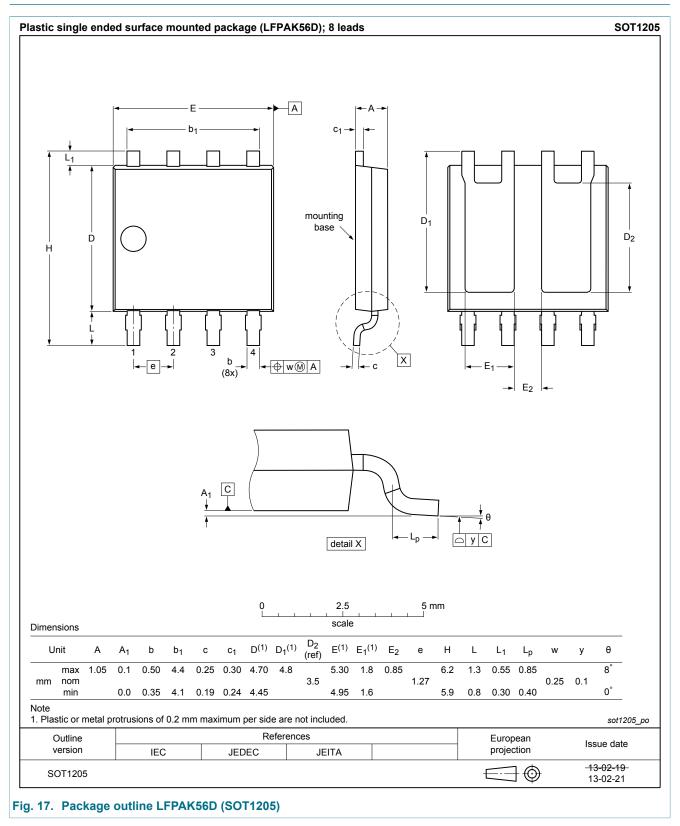


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## 11. Package outline



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Product data sheet

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Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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